

Form PTO-1449 U.S. Department of Commerce  
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Atty. Docket No. 501.30598CC3  
Serial No. (not yet assigned)  
Applicant: MORIOKA et al  
Filing Date: March 14, 2001  
Group:  
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J1033 U.S. PTO  
09/805188  
03/14/01

U.S. Patent Documents

Examiner Initials	Document No.	Date	Name	Class	Subclass	Filing Date If Approp.
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TM  
3,658,420 4/72 Axelrod  
3,771,880 11/73 Bennett  
3,930,155 12/75 Kanomata et al  
4,332,833 6/82 Aspnes et al  
4,376,583 3/83 Alford et al  
4,378,159 3/83 Galbraith  
4,441,124 4/84 Heebner et al  
4,441,268 4/84 Sherman et al  
4,448,532 5/84 Joseph et al  
4,571,685 2/86 Kamoshida  
4,575,922 3/86 Nemiroff  
4,614,427 9/86 Koizumi et al  
4,806,774 2/89 Lin et al  
4,856,904 8/89 Akagawa  
4,939,363 7/90 Bando et al  
4,963,500 10/90 Cogan et al  
5,004,307 4/91 Kino et al  
5,028,778 7/91 Ninomiya et al  
5,055,679 10/91 Ninomiya et al  
5,172,000 12/92 Scheff et al  
5,274,434 12/93 Morioka et al  
5,276,498 1/94 Galbraith et al

TM

Foreign Patent Documents

Document No.	Date	Country	Class	Subclass	Translation Yes      No
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TM 59-65428 4/84 Japan  
D 1257725 9/86 USSR

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Other Documents (including Author, Title, Date, Pertinent Pages, etc.)

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*TM*  
"Simultaneous Observations of Partially Oxidized...", Komiya et al, J. Vac. Sci. Technology, Vol. 12, No. 1, Jan/Feb 1975

*TM*  
"Scanning Laser Senses Wafer Defects", Electronics, Mar. 16, 1978, Vol. 51, No. 6, pp. 48 and 50, Copy 356/237

Examiner

Date Considered

*TM*  
8/11/01

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